

## N-Channel Enhancement Mode Power MOSFET

### Description

The HM30N02K uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

### General Features

- $V_{DS} = 20V, I_D = 30A$
- $R_{DS(ON)} < 10m\Omega @ V_{GS}=10V$  (Typ:8.0m $\Omega$ )

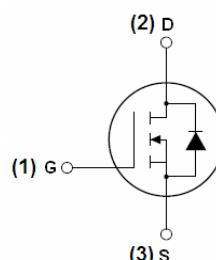
- High density cell design for ultra low  $R_{DS(on)}$
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high  $E_{AS}$
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

### Application

- Power switching application
- Load switching
- Uninterruptible power supply

**100% UIS TESTED!**

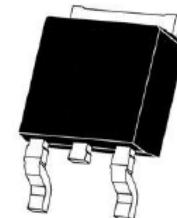
**100%  $\Delta V_{ds}$  TESTED!**



Schematic diagram



Marking and pin assignment



TO-252-2L top view

### Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM30N02K	HM30N02K	TO-252-2L	-	-	-

### Absolute Maximum Ratings ( $T_A=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	20	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Drain Current-Continuous	$I_D$	30	A
Drain Current-Continuous( $T_C=100^\circ C$ )	$I_D (100^\circ C)$	21	A
Pulsed Drain Current	$I_{DM}$	75	A
Maximum Power Dissipation	$P_D$	40	W
Single pulse avalanche energy <sup>(Note 5)</sup>	$E_{AS}$	150	mJ
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 To 175	°C

### Thermal Characteristic

Thermal Resistance, Junction-to-Case <sup>(Note 2)</sup>	$R_{eJC}$	3.8	°C/W
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**Electrical Characteristics ( $T_A=25^\circ\text{C}$  unless otherwise noted)**

Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$	20	-	-	V
Zero Gate Voltage Drain Current	$\text{I}_{\text{DS}}^{\text{SS}}$	$\text{V}_{\text{DS}}=20\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
Gate-Body Leakage Current	$\text{I}_{\text{GSS}}$	$\text{V}_{\text{GS}}=\pm 12\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b> (Note 3)						
Gate Threshold Voltage	$\text{V}_{\text{GS(th)}}$	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$	0.5	0.7	1.2	V
Drain-Source On-State Resistance	$\text{R}_{\text{DS(ON)}}$	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=20\text{A}$	-	8	10	$\text{m}\Omega$
Forward Transconductance	$\text{g}_{\text{FS}}$	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_D=20\text{A}$	10	-	-	S
<b>Dynamic Characteristics</b> (Note 4)						
Input Capacitance	$\text{C}_{\text{iss}}$	$\text{V}_{\text{DS}}=10\text{V}, \text{V}_{\text{GS}}=0\text{V}, \text{F}=1.0\text{MHz}$		900		PF
Output Capacitance	$\text{C}_{\text{oss}}$			162		PF
Reverse Transfer Capacitance	$\text{C}_{\text{rss}}$			105		PF
<b>Switching Characteristics</b> (Note 4)						
Turn-on Delay Time	$t_{\text{d(on)}}$	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=10\text{V}$ $\text{RL}=0.5\Omega, \text{RGEN}=3\Omega$	-	4.5	-	nS
Turn-on Rise Time	$t_r$		-	9.2	-	nS
Turn-Off Delay Time	$t_{\text{d(off)}}$		-	18.7	-	nS
Turn-Off Fall Time	$t_f$		-	3.3	-	nS
Total Gate Charge	$\text{Q}_g$	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=10\text{V}, \text{ID}=20\text{A}$		15		nC
Gate-Source Charge	$\text{Q}_{\text{gs}}$			1.8		nC
Gate-Drain Charge	$\text{Q}_{\text{gd}}$			2.8		nC
<b>Drain-Source Diode Characteristics</b>						
Diode Forward Voltage (Note 3)	$\text{V}_{\text{SD}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_S=20\text{A}$	-	-	1.2	V
Diode Forward Current (Note 2)	$\text{I}_S$	-	-	-	30	A
Reverse Recovery Time	$t_{\text{rr}}$	$\text{TJ} = 25^\circ\text{C}, \text{IF} = 20\text{A}$ $\text{di/dt} = 100\text{A}/\mu\text{s}$ (Note 3)	-	18	-	nS
Reverse Recovery Charge	$\text{Q}_{\text{rr}}$		-	9.5	-	nC
Forward Turn-On Time	$t_{\text{on}}$	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

**Notes:**

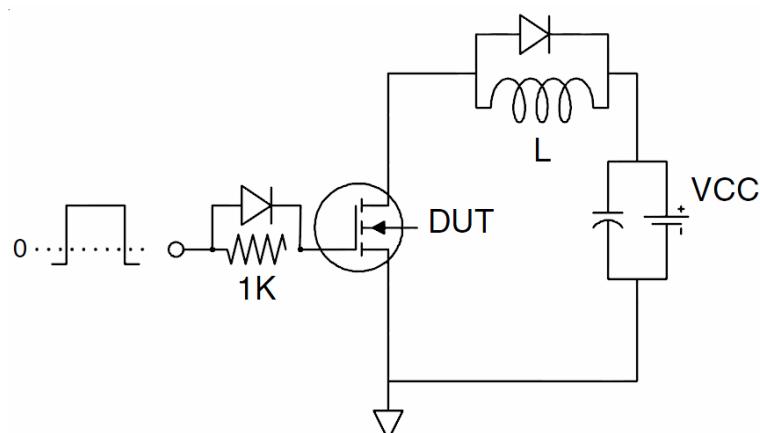
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board,  $t \leq 10$  sec.
3. Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$ .
4. Guaranteed by design, not subject to production
5. EAS condition:  $\text{Tj}=25^\circ\text{C}, \text{V}_{\text{DD}}=10\text{V}, \text{V}_{\text{G}}=10\text{V}, \text{L}=0.5\text{mH}, \text{Rg}=25\Omega$

### Test circuit

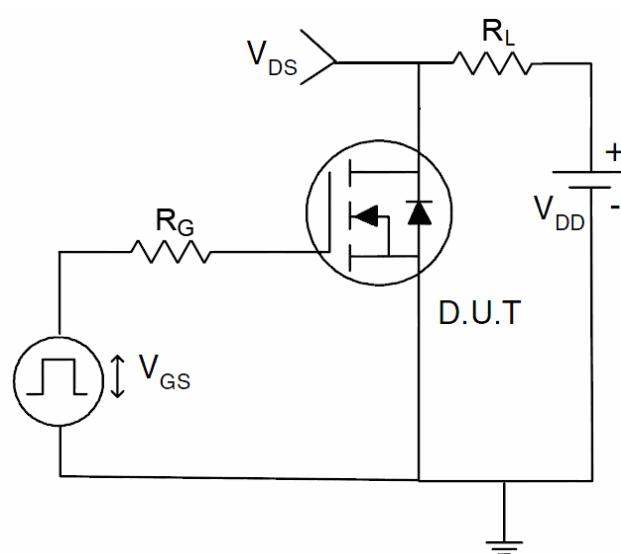
#### 1) E<sub>AS</sub> test Circuits



#### 2) Gate charge test Circuit:



#### 3) Switch Time Test Circuit:



### Typical Electrical and Thermal Characteristics (Curves)

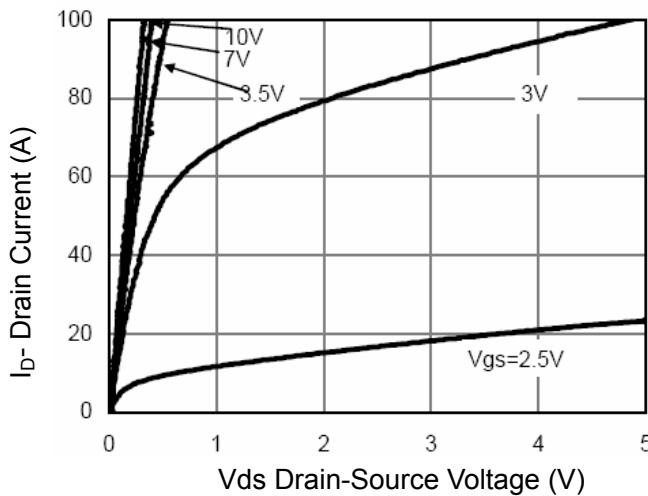


Figure 1 Output Characteristics

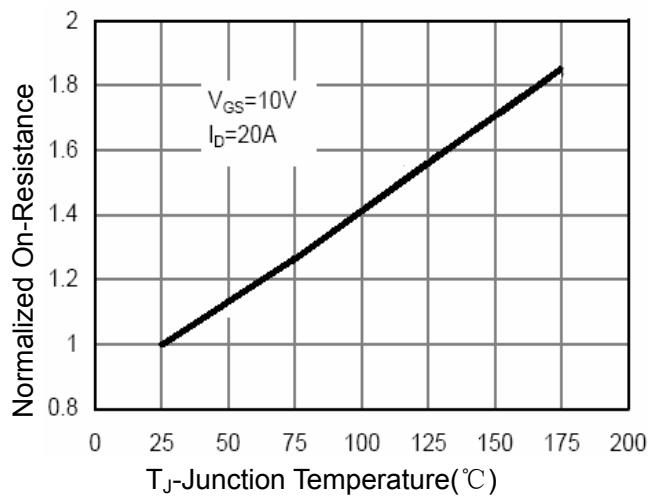


Figure 4 Rdson-Junction Temperature

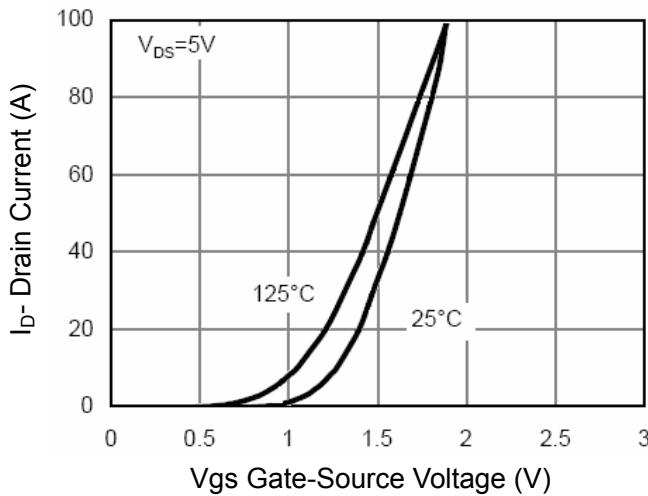


Figure 2 Transfer Characteristics

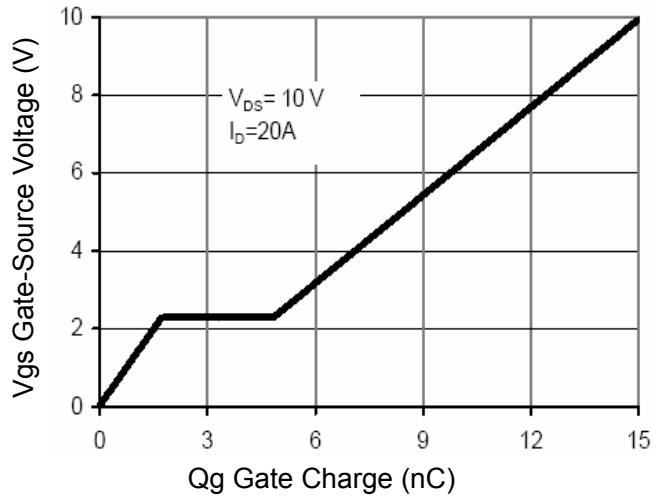


Figure 5 Gate Charge

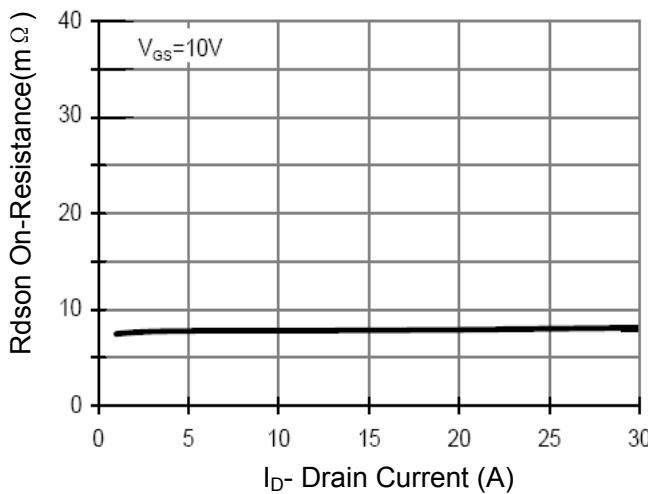


Figure 3 Rdson-Drain Current

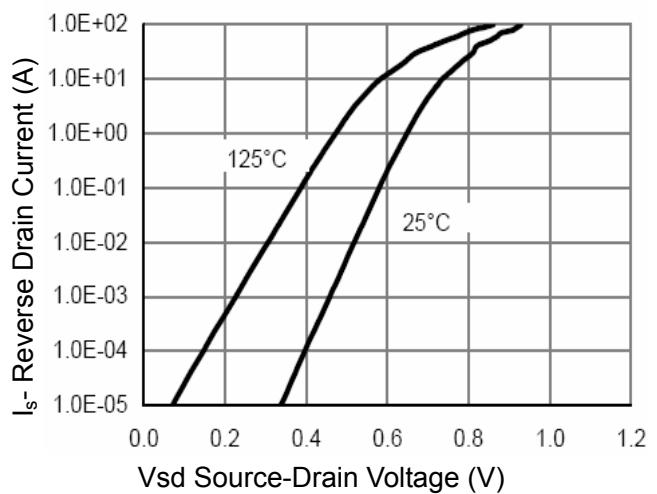


Figure 6 Source-Drain Diode Forward

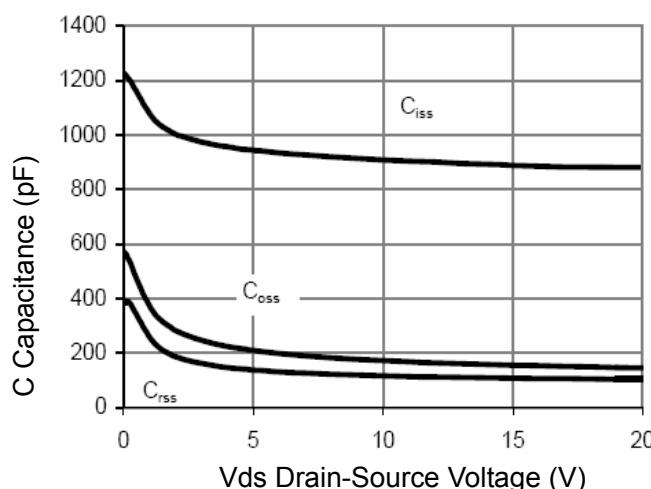


Figure 7 Capacitance vs Vds

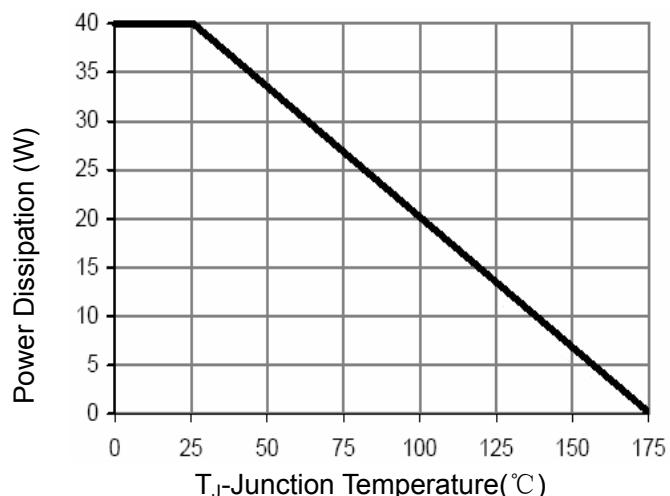


Figure 9 Power De-rating

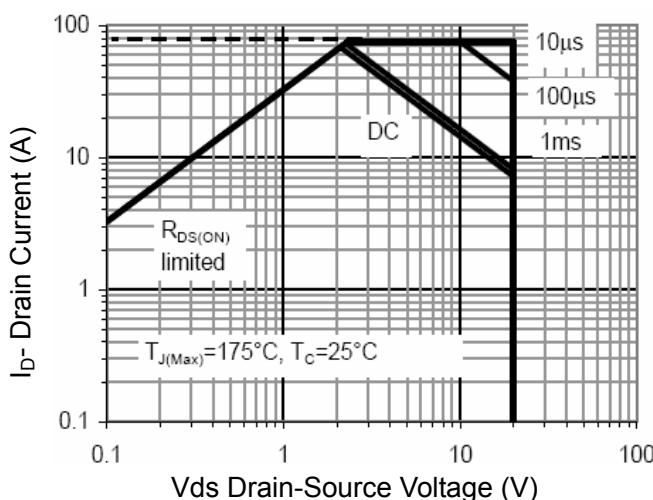


Figure 8 Safe Operation Area

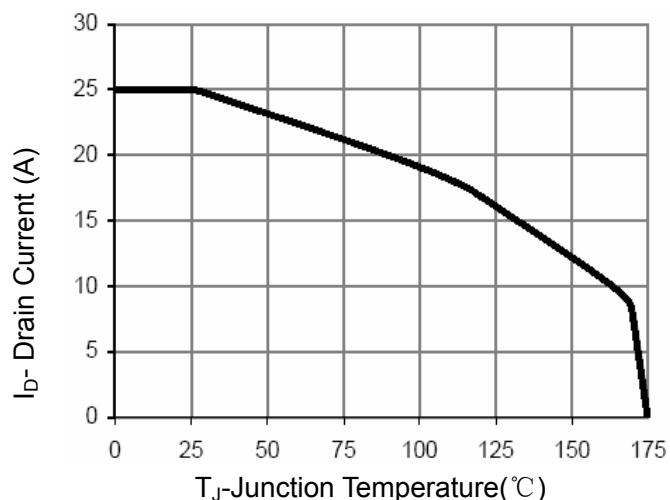


Figure 10 Current De-rating

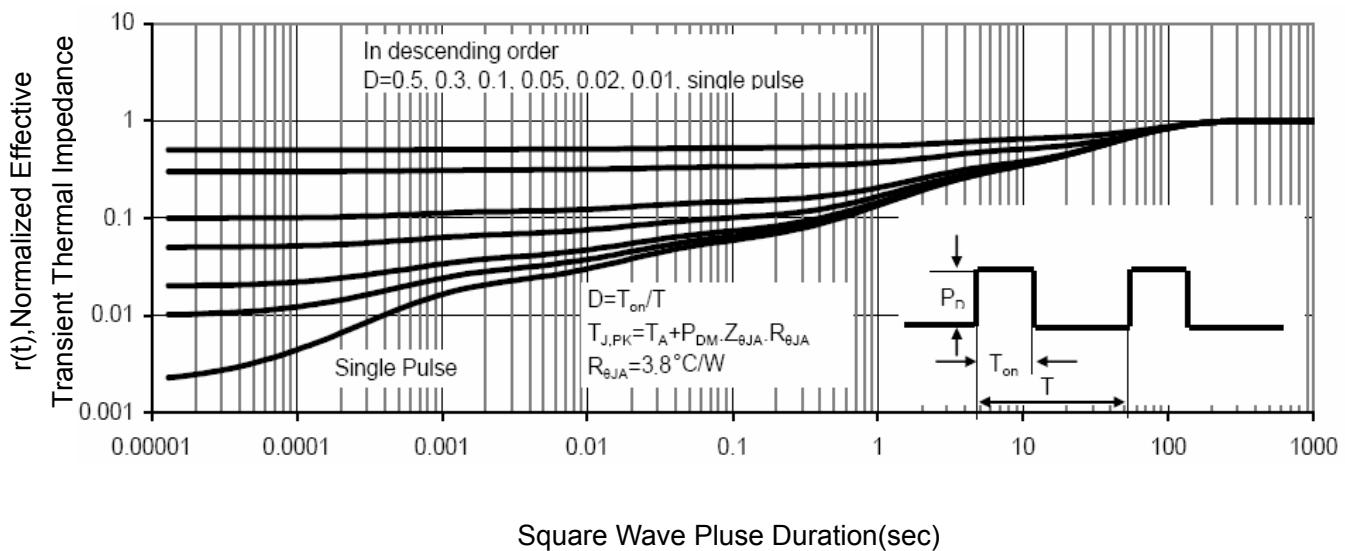
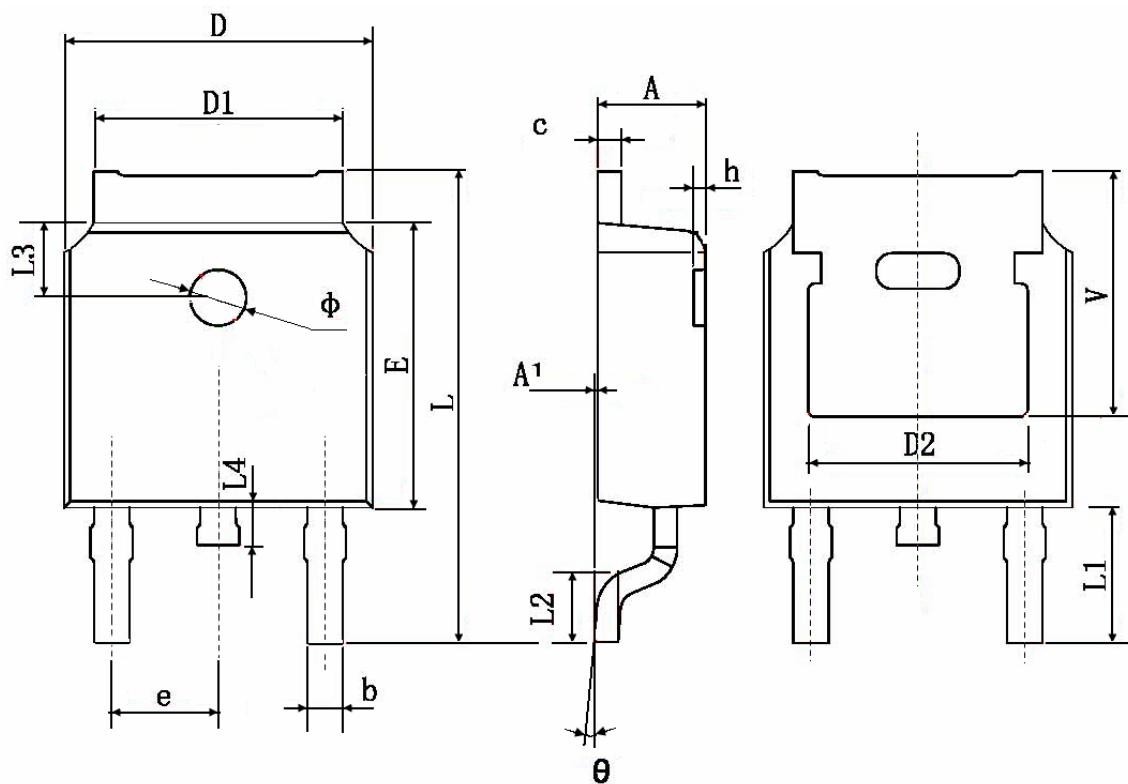


Figure 11 Normalized Maximum Transient Thermal Impedance

TO-252 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	0.483 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	